# MOSFET – Power, Single, N-Channel 80 V, 2.8 mΩ, 157 A

#### **Features**

- Small Footprint (5x6 mm) for Compact Design
- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Q<sub>G</sub> and Capacitance to Minimize Driver Losses
- NVMFS6H801NWF Wettable Flank Option for Enhanced Optical Inspection
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free and are RoHS Compliant

## **MAXIMUM RATINGS** (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			$V_{DSS}$	80	V
Gate-to-Source Voltage	Э		V <sub>GS</sub>	±20	V
Continuous Drain		T <sub>C</sub> = 25°C	I <sub>D</sub>	157	Α
Current R <sub>0JC</sub> (Notes 1, 3)	Steady	T <sub>C</sub> = 100°C		111	
Power Dissipation	State	T <sub>C</sub> = 25°C	$P_{D}$	166	W
R <sub>θJC</sub> (Note 1)		T <sub>C</sub> = 100°C		83	
Continuous Drain		T <sub>A</sub> = 25°C	I <sub>D</sub>	23	Α
Current R <sub>0JA</sub> (Notes 1, 2, 3)	Steady	T <sub>A</sub> = 100°C		16	
Power Dissipation	State	T <sub>A</sub> = 25°C	$P_{D}$	3.8	W
R <sub>θJA</sub> (Notes 1, 2)		T <sub>A</sub> = 100°C		1.9	
Pulsed Drain Current	$T_A = 25^{\circ}C, t_p = 10 \mu s$		I <sub>DM</sub>	900	Α
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +175	°C
Source Current (Body Diode)			I <sub>S</sub>	138	Α
Single Pulse Drain-to-Source Avalanche Energy (I <sub>L(pk)</sub> = 12.2 A)			E <sub>AS</sub>	960	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

#### THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State	$R_{\theta JC}$	0.9	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	39	

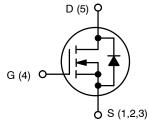
- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Surface-mounted on FR4 board using a 650 mm<sup>2</sup>, 2 oz. Cu pad.
- Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



## ON Semiconductor®

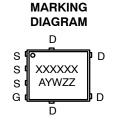
#### www.onsemi.com

V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
80 V	2.8 mΩ @ 10 V	157 A



**N-CHANNEL MOSFET** 





XXXXXX = 6H801N

(NVMFS6H801N) or

801NWF

(NVMFS6H801NWF) = Assembly Location

A = Assembly Local
Y = Year
W = Work Week
ZZ = Lot Traceability

#### **ORDERING INFORMATION**

See detailed ordering, marking and shipping information in the package dimensions section on page 5 of this data sheet.

## **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise specified)

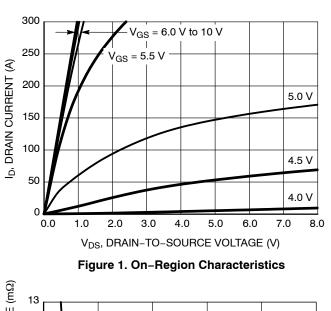
Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS				•	•	•	•
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		80			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> / T <sub>J</sub>				38		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>					10	
		V <sub>DS</sub> = 80 V	T <sub>J</sub> = 125°C			100	μΑ
Gate-to-Source Leakage Current	I <sub>GSS</sub>	$V_{DS} = 0 V, V_{GS}$	= 20 V			100	nA
ON CHARACTERISTICS (Note 4)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_D =$	= 250 μA	2.0		4.0	V
Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				7.2		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 50 A		2.3	2.8	mΩ
Forward Transconductance	9FS	V <sub>DS</sub> =15 V, I <sub>D</sub>	= 50 A		128		S
CHARGES, CAPACITANCES & GATE RE	SISTANCE						
Input Capacitance	C <sub>ISS</sub>				4120		
Output Capacitance	C <sub>OSS</sub>	V <sub>GS</sub> = 0 V, f = 1 MHz	z, V <sub>DS</sub> = 40 V		586		pF
Reverse Transfer Capacitance	C <sub>RSS</sub>				22		]
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 40	0 V; I <sub>D</sub> = 50 A		64		
Threshold Gate Charge	Q <sub>G(TH)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 40 V; I <sub>D</sub> = 50 A			11		
Gate-to-Source Charge	Q <sub>GS</sub>				19		nC
Gate-to-Drain Charge	Q <sub>GD</sub>				13		
Plateau Voltage	V <sub>GP</sub>				5.0		V
SWITCHING CHARACTERISTICS (Note 5	5)						
Turn-On Delay Time	t <sub>d(ON)</sub>				25		
Rise Time	t <sub>r</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub>	s = 64 V,		74		1
Turn-Off Delay Time	t <sub>d(OFF)</sub>	$I_D = 50 \text{ A}, R_G = 2.5 \Omega$			70		ns -
Fall Time	t <sub>f</sub>				19		
DRAIN-SOURCE DIODE CHARACTERIS	STICS						
Forward Diode Voltage	V <sub>SD</sub>	V <sub>GS</sub> = 0 V,	T <sub>J</sub> = 25°C		0.8	1.2	.,
		1 50 4	T <sub>J</sub> = 125°C		0.7		- V
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V, dIS/dt} = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 50 \text{ A}$			64		
Charge Time	t <sub>a</sub>				36		ns
Discharge Time	t <sub>b</sub>				28		1
Reverse Recovery Charge	Q <sub>RR</sub>				98		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Pulse Test: pulse width  $\leq 300~\mu s$ , duty cycle  $\leq 2\%$ .

5. Switching characteristics are independent of operating junction temperatures.

## **TYPICAL CHARACTERISTICS**



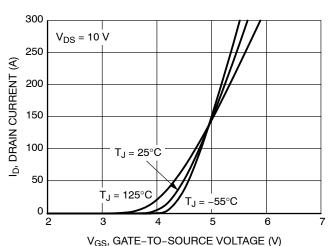
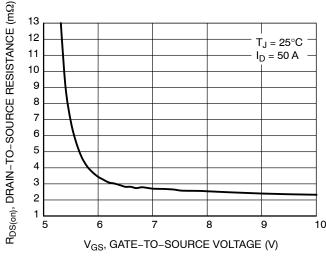


Figure 2. Transfer Characteristics



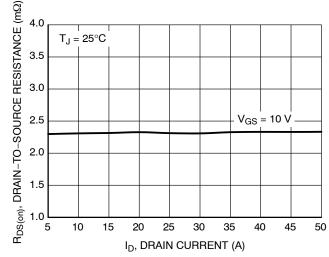
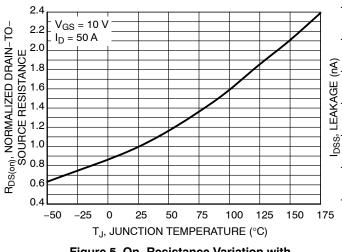


Figure 3. On-Resistance vs. Gate-to-Source Voltage

Figure 4. On-Resistance vs. Drain Current and Gate Voltage



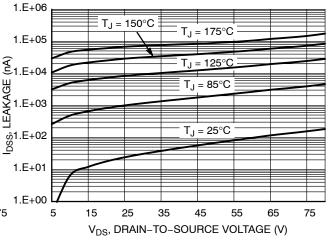


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Voltage

## **TYPICAL CHARACTERISTICS**

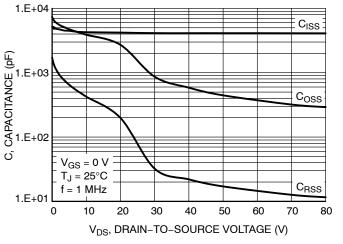


Figure 7. Capacitance Variation

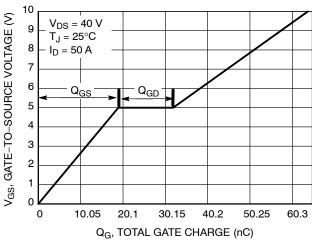


Figure 8. Gate-to-Source vs. Total Charge

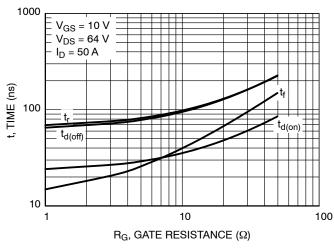


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

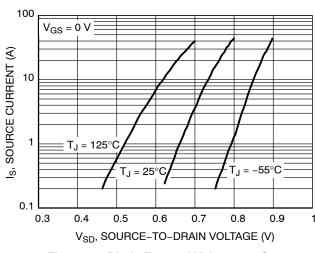


Figure 10. Diode Forward Voltage vs. Current

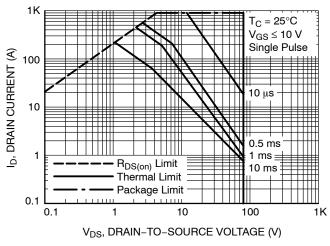


Figure 11. Maximum Rated Forward Biased Safe Operating Area

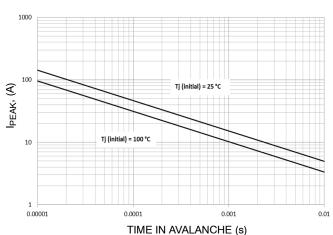


Figure 12. I<sub>PEAK</sub> vs. Time in Avalanche

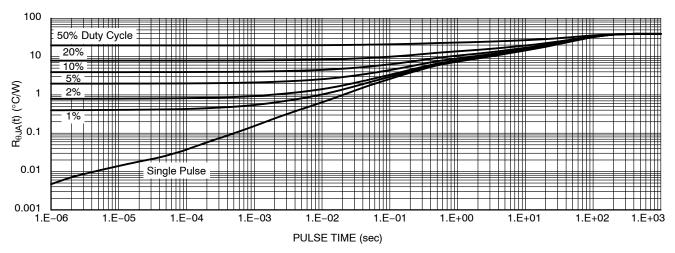


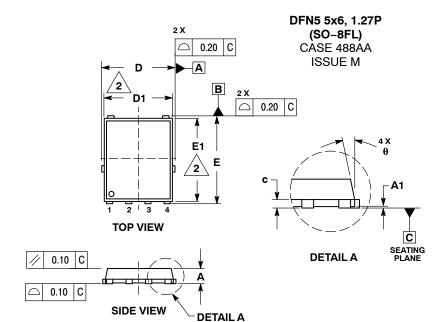
Figure 13. Thermal Characteristics

#### **DEVICE ORDERING INFORMATION**

Device	Marking	Package	Shipping <sup>†</sup>
NVMFS6H801NT1G	6H801N	DFN5 (Pb-Free)	1500 / Tape & Reel
NVMFS6H801NWFT1G	801NWF	DFN5 (Pb-Free, Wettable Flanks)	1500 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

#### PACKAGE DIMENSIONS



#### NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- 2. CONTROLLING DIMENSION: MILLIMETER.
  3. DIMENSION D1 AND E1 DO NOT INCLUDE
- MOLD FLASH PROTRUSIONS OR GATE BURRS

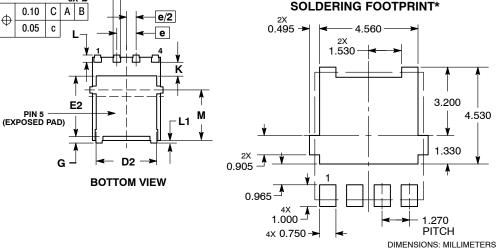
	MILLIMETERS			
DIM	MIN	NOM	MAX	
Α	0.90	1.00	1.10	
A1	0.00		0.05	
b	0.33	0.41	0.51	
С	0.23	0.28	0.33	
D	5.00	5.15	5.30	
D1	4.70	4.90	5.10	
D2	3.80	4.00	4.20	
E	6.00	6.15	6.30	
E1	5.70	5.90	6.10	
E2	3.45	3.65	3.85	
е	1.27 BSC			
G	0.51	0.575	0.71	
K	1.20	1.35	1.50	
L	0.51	0.575	0.71	
L1	0.125 REF			
М	3.00	3.40	3.80	
θ	0 °		12 °	

#### STYLE 1:

PIN 1. SOURCE

- SOURCE
- SOURCE GATE
- DRAIN





\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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